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Australian Standard®
2547.1.1—1986

SEMICONDUCTOR DEVICES—
Part 1.1—DISCRETE DEVICES—
GENERAL

STANDARDS ASSOCIATION OF AUSTRALIA
Incorporated by Royal Charter

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The following interests are represented on Committee TE/12:

Department of Defence

Department of Industry, Technology and Commerce

Confederation of Australian Industry

Institution of Radio and Electronics Engineers, Australia

Telecom Australia

AUSTRALIAN STANDARD

SEMICONDUCTOR DEVICES—
Part 1.1
DISCRETE DEVICES—
GENERAL

AS 2547.1.1—1986

First published 1986

See also Preface (p.2) and
Cross reference index (p.7)

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PREFACE

This standard was prepared by the Association's Committee on Semiconductors and Devices. It is reproduced from IEC 747.1:1983 and is one of the standards prepared by IEC/TC 47, Semiconductor Devices.

This standard is one of a series of standards published under the generic specification AS 2547. This standard supersedes:

- the existing AS 2547 series (published in 1982 and 1983 and identical to equivalent parts of IEC 147 published between 1966 and 1981);
- AS C366, Part 4—1978 and Part 5—1978 (equivalent to IEC 147-4, IEC 147-5 and IEC 147-5A);
- AS C367 (endorsement of IEC 148—1969);
- AS 1967 (identical to IEC 147-1D and 1E).

The purpose of IEC 747 is to reorganize into a device oriented publication, the material originally presented in the IEC 147* series and IEC 148† on semiconductor devices and letter symbols representing them is now republished as follows:

(a) Specific requirements for integrated circuits—now IEC 748.

(b) Mechanical and climatic test methods—now IEC 749.

It was in view of the above reorganization that Committee TE/12 agreed to integrate the entire series into one series of Australian standards using the generic designation AS 2547. The relationship with the three IEC standards is as follows:

(i) Part 1.1 onwards—identical with the IEC 747 series.

(ii) Part 2.1 onwards—identical with the IEC 748 series.

(iii) Part 3.1—identical with IEC 749.

For the purpose of this Australian standard and all other standards in this AS 2547 series, the text of the reproduced IEC Publications should be modified as follows:

A. *Terminology.* The words 'Australian Standard' should replace the words 'IEC Publication' wherever they appear.

B. *Cross-references.* The reference to IEC Publications should be replaced by references to the appropriate Australian Standards as follows:

Reference to IEC Publications		*Appropriate Australian Standard*	
IEC 27	Letter symbols to be used in electrical technology	AS 1046	Letter Symbols for Use in Electrotechnology
IEC 50	International Electrotechnical Vocabulary	AS 1852	International Electrotechnical Vocabulary
IEC 191	Mechanical standardization of semiconductor devices	AS C379	Mechanical Standardization of Semiconductor Devices
IEC 319	Presentation of reliability data on electronic components	AS 2350	Presentation of Reliability Data on Electronic and Similar Components
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* IEC 147, Essential ratings and characteristics of semiconductor devices and general principles of measuring methods.

† IEC 148, Letter symbols for semiconductor devices and integrated microcircuits.

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